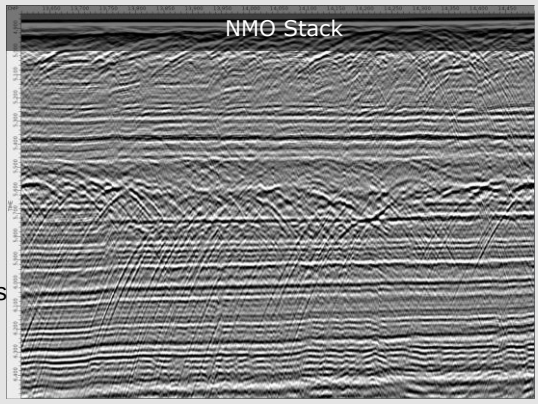
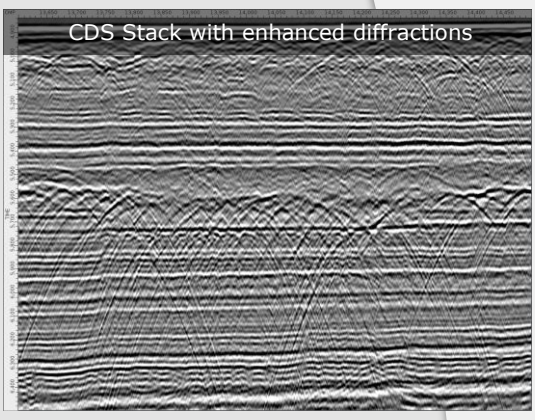
Common Diffraction Stack and EDIT Migration

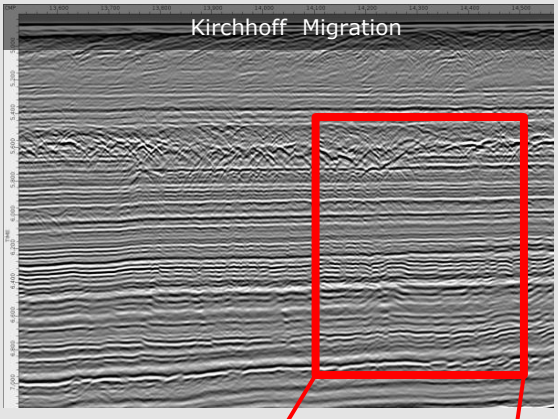
The new E.D.I.T method for fracture enhancement and diffraction imaging is based on the Common Reflection Surface technology.

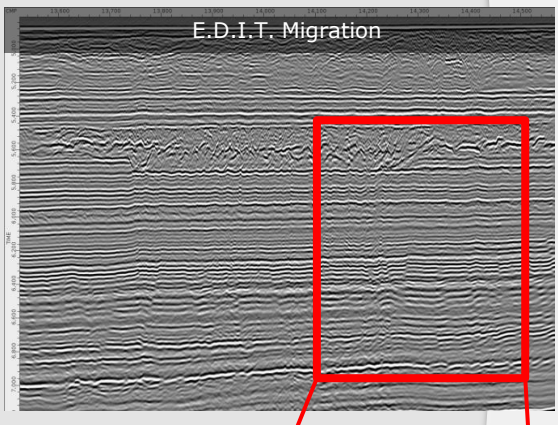
The CRS operator has been reformulated to enable a data driven simultaneous search for diffraction attributes in 2D and 3D seismic data. These can be used to both, enhance diffractions and perform a time migration.

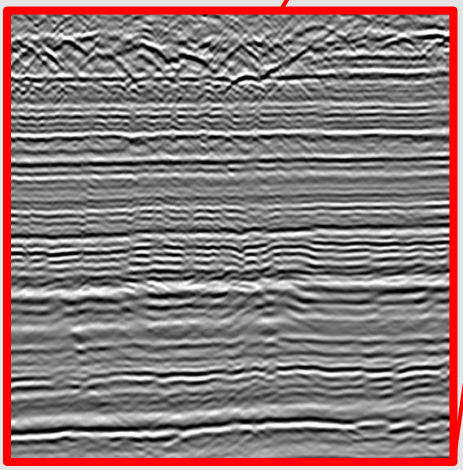


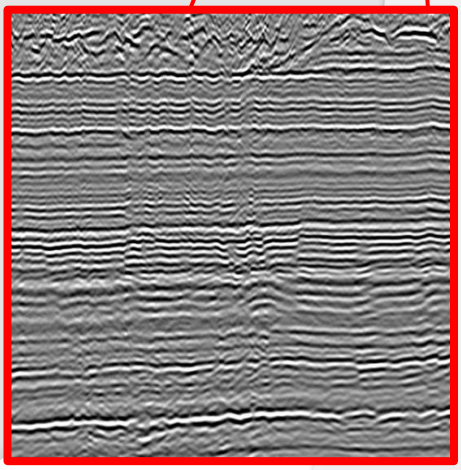


The Enhanced Diffraction Image Technology (E.D.I.T.) enhances subtle faults and lineaments in otherwise simple geology, which is of special interest in shale-gas exploration. Moreover, migration operator noise is limited to a minimum, due to the data driven approach.









The zooms show detailed structures in every depth/time level, which were not as clear with a standard Kirchhoff migration. The E.D.I.T. migration works on the improved image from the CDS application and migrates the energy along the diffractions to the apex. The effect is the limitation in oprator noise and an improvement in resolution.

Burgwedeler Str. 89, 30916 Isernhagen, Germany +49 (0)511 7240452 www.teec.de

TEEC Geophysics